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09/862881
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In the United States Patent and Trademark Office

Appn. Number: N.A.
Appn. Filed: N.A.
Applicant(s): Hertziger, Green, Synowicki
Appn. Title: Methodology For Improving Precision of Data
Examiner/GAU: _____ 1324

Mailed: With Application
At: _____

Information Disclosure Statement

Commissioner of Patents and Trademarks
Washington, District of Columbia 20231

Sir:

Attached is a completed Form PTO-1449 and copies of the pertinent parts of the references cited thereon.

Following are comments on these references pursuant to Rule 98:

INFORMATION DISCLOSURE

Patent No. 4,832,491 to Sharpe et al. describes a method of using electromagnetic radiation to investigate a sample system, involving using a monochromator to set a wavelength, obtaining reference data, obtaining sample system data, forming a ratio of the sample system and reference data, and repeating said steps for additional wavelengths.

Patent, No. 3,790,798 to Sternberg et al., describes a single beam system wherein reference data is obtained with filters in place in said system which pass wavelengths other than those which are absorbed by a sample analyte, (eg. gas in a sample containing cell). Said 798 Patent describes obtaining both sample and reference data and forming a ratio therebetween.

Patent to Fukasawa et al., No. 4,577,106, describes a double beam spectrophotometer which contains means for allowing acquisition of dark, reference, sample and reference data, in that order.

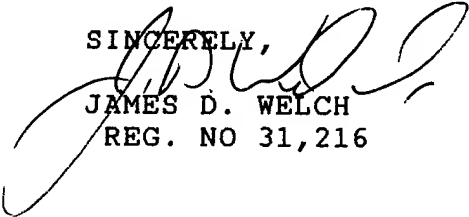
Patent to George, No. 3,986,776 describes baseline compensation in a dual beam spectrophotometer. During a calibration run a baseline error signal is generated, and said error signal is used to adjust a ratio of a sample to baseline signal during sample data acquisition.

Patent No. 4,079,256 to Ford et al., describes a double-beam system in which two evaluations are combined to produce a derived reference signal in a situation wherein sample and reference

signals do not occur at the same time, because a single spectrophotometer detector system it utilized.

Patents 4,084,²⁴⁸~~282~~ and 3,579,105 to Scott describe dual beam systems in which in the calibration run two beams are compared at each wavelength and adjustment disparities are calculated, said adjustments being applied during sample runs.

SINCERELY,


JAMES D. WELCH
REG. NO 31,216

LIST OF PRIOR ART CITED BY APPLICANT
(Use several sheets if necessary)

APPLICANT

Hertzinger et al.

FILING DATE

GROUP

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U.S. PATENT DOCUMENTS

| EXAMINER INITIAL | DOCUMENT NUMBER | DATE | NAME | CLASS | SUBCLASS | FILING DATE IF APPROPRIATE |
|---------------------|-----------------|---------|------------------|-------|----------|-------------------------------|
| AA | 4832491 | 5/1985 | Sharpe et al. | 356 | 326 | |
| AB | 3790798 | 2/1974 | Sternberg et al. | 250 | 345 | |
| AC | 4577106 | 3/1986 | Fukushima et al. | 250 | 347 | |
| AD | 3986776 | 10/1976 | George | 356 | 88 | |
| AE | 4079258 | 3/1978 | Ferd et al. | 250 | 343 | |
| AF | 4084248 | 4/1978 | Scott | 364 | 571 | |
| AG | 3579105 | 5/1971 | Scott | 324 | 99 | |
| AH | | | | | | |
| AI | | | | | | |
| AJ | | | | | | |
| AK | | | | | | |

FOREIGN PATENT DOCUMENTS

| | DOCUMENT NUMBER | DATE | COUNTRY | CLASS | SUBCLASS | TRANSLATION | |
|----|-----------------|------|---------|-------|----------|-------------|----|
| | | | | | | YES | NO |
| AL | | | | | | | |
| AM | | | | | | | |

OTHER PRIOR ART (Including Author, Title, Date, Pertinent Pages, Etc.)

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| AR | |
| AS | |

EXAMINER

DATE CONSIDERED

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.